

Substitute for form 1449/PTO

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Sheet 1

of 2

Complete if Known

Application Number ~~106~~ 10/622,247
Filing Date
First Named Inventor Lim
Art Unit 2857
Examiner Name PHUONG HUYNH
Attorney Docket Number CS01-150

U. S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
PH		US- 6,403,389B1 ✓	04/11/2002	Chang et al	
		US- 5,627,101 ✓	5/6/1997	Lin et al.	
		US- 5,987,398 ✓	11/16/1999	Halverson et al.	
		US- 5,883,437 B ✓	3/16/1999	Maruyama et al.	
		US- 6,466,038 ✓	10/15/2002	Pekin	
		US- 5,514,974 B ✓	5/7/1996	Bouldin	
		US- 6,087,189 ✓	7/11/2000	Huang	
PH		US- 5,552,718 ✓	5/3/1996	Bruce	
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FOREIGN PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Foreign Patent Document Country Code ³ Number ⁴ Kind Code ⁵ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages Or Relevant Figures Appear

Examiner
Signature

/Phuong Huynh/

Date
Considered

07/06/2006

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. ¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

This collection of information is required by 37 CFR 1.97 and 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, Washington, DC 20231. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, Washington, DC 20231.

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Substitute for form 1449/PTO

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

Complete if Known

Application Number	180 10/622,247
Filing Date	
First Named Inventor	Lim
Art Unit	2857
Examiner Name	PHUONG HUYNH
Attorney Docket Number	cs01-50

Sheet 2 of 2

NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
PH		PLUSQUELLIC et al., "Identification of defective CMOS devices using Correlation and Regression Analysis ... Data" website www.csee.umbc.edu	/

Examiner Signature	/Phuong Huynh/	Date Considered	07/06/2006
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Applicant's unique citation designation number (optional). ² Applicant is to place a check mark here if English language Translation is attached.

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1989
S/N TBD
Docket: CS01-150
Group art unit : — TBD

The following Patents and/or Publication are submitted to comply with the duty to disclose under CFR 1.97-1.99 and 37 CFR 1.56. Copies of each document is included herewith.

US 6,403,389B1 (Chang et al.) shows a method for measuring sheet resistance.

US 5,627,101 (Lin et al.) shows a test method for a electro migration using a Metal and Poly test structure.

US 5,987,398 (Halverson et al.) shows a method for SPC for a process having a non-constant mean of a response variable.

US 5,883,437 (Maruyama et al.) discloses a method for applying a time varying voltage between the electrode and wiring pattern at different locations so as to detect a current flow and determine a defect by a variation in the detected current flow at the different locations and a portion of the defect.

1419
S/N TBD

Docket: CS01-150

Group art unit : ___ TBD

US 6,466,038 (Pekin, et al.) shows a method for non-isothermal electro migration testing of interconnects.

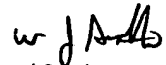
US 5,514,974 (Bouldin) shows a method for testing for metal failures by using 2 different test structures.

US 6,087,189 (Huang) shows test structure to monitor silicide.

US 5,552,718 (Bruce et al.) shows a test structure for space and line measurement.

Plusquellic et al., "Identification of defective CMOS devices using Correlation and Regression Analysis of Frequency Domain Transient Signal data", retrieved from website <http://www.csee.umbc.edu/~plusquel/pubs/itc97.pdf> on about May 20, 2003. No publication date listed.

Sincerely,



William J. Stoffel

Reg. No. 39,390

Customer number 30,402